
Editorial

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Biographical notes: Angsuman Sarkar is presently serving as a Professor of Electronics and Communication Engineering in Kalyani Government Engineering College, West Bengal. He received his MTech in VLSI and Microelectronics from Jadavpur University. He completed his PhD from Jadavpur University in 2013. His current research interest span around study of short channel effects of sub 100 nm MOSFETs and nanodevice modelling. He is a life member of Indian Society for Technical Education (ISTE) and Institution of Engineers (India) and also Senior Member of IEEE and current Chair of Electron Device Society, Kolkata Section. He has authored many books, number of research papers in national and international refereed journals and conferences.

Jyotsna Kumar Mandal is the Former Dean of FETM, and was KU for two consecutive terms. He has teaching and research experience spanning 29 years and completed four AICTE and one state government project. He is a life member of the CSI, CRSI, a member of the ACM, and Fellow of IETE. He was also Honorary Vice Chairman and Chairman of the CSI. He has delivered over 100 lectures and organized more than 25 national and international conferences. He has produced 20 PhD degrees, three scholars submitted and pursuing eight. He has supervised three MPhil and more than 50 MTech dissertations and more than 100 MCA dissertations. He is an editorial board member and corresponding editor of the Proceedings of Science Direct, IEEE and other conferences as well as guest editor of the *MST Journal*. He has published more than 400 research articles, and six books.

This special issue of *International Journal on Nanoparticles* on ‘Advanced nanoscale devices/MEMS/NEMS for application in microsystems’ is devoted to the modelling, simulation and advanced nanoscale devices, MEMS/NEMS. The aim of this special issue is to provide an overview of the recent development and advancement in the field of electronic devices. This special issue consists of four articles carefully selected from the papers presented at the ‘Devices for Integrated Circuits (DevIC 2019)’ conference held on 23–24 March 2019 at Kalyani Government Engineering College, Kalyani, India.

We hope that you will find this special issue interesting and that you will consider participation in the future ‘DevIC’ conferences.